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#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Obsolete
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I <sup>2</sup> C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	38
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	16К х 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 12x8/10b; D/A 2x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	52-LQFP
Supplier Device Package	52-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f104jgafa-v0

Email: info@E-XFL.COM

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## 1.5.6 48-pin products



**Note** Mounted on the 96 KB or more code flash memory products.



# 2. ELECTRICAL SPECIFICATIONS (TA = -40 to $+85^{\circ}$ C)

This chapter describes the following electrical specifications.

Target products A: Consumer applications  $T_A = -40$  to  $+85^{\circ}C$ 

R5F104xxAxx

- D: Industrial applications TA = -40 to +85°C R5F104xxDxx
- G: Industrial applications when TA = -40 to +105°C products is used in the range of TA = -40 to +85°C R5F104xxGxx
- Caution 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
- Caution 2. With products not provided with an EVDD0, EVDD1, EVSS0, or EVSS1 pin, replace EVDD0 and EVDD1 with VDD, or replace EVSS0 and EVSS1 with VSS.
- Caution 3. The pins mounted depend on the product. Refer to 2.1 Port Functions to 2.2.1 Functions for each product in the RL78/G14 User's Manual.



- Note 1. Total current flowing into VDD, EVDD0, and EVDD1, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0, and EVDD1, or Vss, EVss0, and EVss1. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, D/A converter, comparator, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
   Note 2. During HALT instruction execution by flash memory.
- Note 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- **Note 4.** When high-speed system clock and subsystem clock are stopped.
- **Note 5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.
- Note 6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
- Note 7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.
  - HS (high-speed main) mode:  $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{@}1 \text{ MHz}$  to 32 MHz
    - 2.4 V  $\leq$  VDD  $\leq$  5.5 V@1 MHz to 16 MHz
  - LS (low-speed main) mode:  $1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{@}1 \text{ MHz}$  to 8 MHz
  - LV (low-voltage main) mode:  $1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}_{\textcircled{O}}1 \text{ MHz}$  to 4 MHz
- Note 8. Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remark 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
- Remark 2. fHOCO: High-speed on-chip oscillator clock frequency (64 MHz max.)
- **Remark 3.** file: High-speed on-chip oscillator clock frequency (32 MHz max.)
- **Remark 4.** fsuB: Subsystem clock frequency (XT1 clock oscillation frequency)
- Remark 5. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C



#### (2) I<sup>2</sup>C fast mode

#### (TA = -40 to +85°C, 1.6 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

Parameter	Symbol	C	Conditions		Conditions HS (high-spectrum) mode		h-speed mode	LS (lov main)	/-speed mode	LV (low-voltage main) mode		Unit
					MAX.	MIN.	MAX.	MIN.	MAX.			
SCLA0 clock frequency	fsc∟	Fast mode:	$2.7~V \leq EV_{DD0} \leq 5.5~V$	0	400	0	400	0	400	kHz		
		fc∟k ≥ 3.5 MHz	$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$	0	400	0	400	0	400	kHz		
Setup time of restart condi-	tsu: STA	$2.7~V \leq EV_{DD0} \leq$	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$			0.6		0.6		μs		
tion		$1.8 \text{ V} \leq EV_{DD0} \leq$	5.5 V	0.6		0.6		0.6		μs		
Hold time Note 1	thd: STA	$2.7~V \leq EV_{DD0} \leq$	$1.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$			0.6		0.6		μs		
		$1.8 \text{ V} \leq EV_{DD0} \leq$	5.5 V	0.6		0.6		0.6		μs		
Hold time when SCLA0 = "L" tLow		$2.7~V \leq EV_{DD0} \leq 5.5~V$		1.3		1.3		1.3		μs		
		$1.8 \text{ V} \leq EV_{DD0} \leq$	$1.8 \text{ V} \leq EV_{\text{DD0}} \leq 5.5 \text{ V}$			1.3		1.3		μs		
Hold time when SCLA0 = "H"	tніgн	$2.7~V \leq EV_{DD0} \leq$	5.5 V	0.6		0.6		0.6		μs		
		$1.8~V \leq EV_{DD0} \leq$	5.5 V	0.6		0.6		0.6		μs		
Data setup time (reception)	tsu: dat	$2.7~V \leq EV_{DD0} \leq$	5.5 V	100		100		100		ns		
		$1.8~V \leq EV_{DD0} \leq$	$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}$			100		100		ns		
Data hold time (transmission)	thd: dat	$2.7~V \leq EV_{DD0} \leq$	5.5 V	0	0.9	0	0.9	0	0.9	μs		
Note 2		$1.8 \text{ V} \leq EV_{\text{DD0}} \leq$	5.5 V	0	0.9	0	0.9	0	0.9	μs		
Setup time of stop condition	tsu: sto	$2.7~V \leq EV_{\text{DD0}} \leq$	5.5 V	0.6		0.6		0.6		μs		
		$1.8 \text{ V} \leq EV_{DD0} \leq$	5.5 V	0.6		0.6		0.6		μs		
Bus-free time	tвuғ	$2.7 \text{ V} \leq EV_{DD0} \leq$	5.5 V	1.3		1.3		1.3		μs		
		$1.8~V \leq EV_{\text{DD0}} \leq$	5.5 V	1.3		1.3		1.3		μs		

Note 1. The first clock pulse is generated after this period when the start/restart condition is detected.

Note 2. The maximum value (MAX.) of the DEAT is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

- Caution The values in the above table are applied even when bit 2 (PIOR02) in the peripheral I/O redirection register 0 (PIOR0) is 1. At this time, the pin characteristics (IOH1, IOL1, VOH1, VOL1) must satisfy the values in the redirect destination.
- **Remark** The maximum value of C<sub>b</sub> (communication line capacitance) and the value of R<sub>b</sub> (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode:  $C_b$  = 320 pF,  $R_b$  = 1.1 k $\Omega$ 



(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI0, ANI2 to ANI14, ANI16 to ANI20

(TA = -40 to +85°C, 2.4 V  $\leq$  VDD  $\leq$  5.5 V, 1.6 V  $\leq$  EVDD = EVDD1  $\leq$  VDD, Vss = EVss0 = EVss1 = 0 V, Reference voltage (+) = VBGR <sup>Note 3</sup>, Reference voltage (-) = AVREFM = 0 V <sup>Note 4</sup>, HS (high-speed main) mode)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8			bit
Conversion time	tCONV	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±0.60	% FSR
Integral linearity error Note 1	ILE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution	$2.4~V \leq V_{DD} \leq 5.5~V$			±1.0	LSB
Analog input voltage	Vain			0		VBGR Note 3	V

**Note 1.** Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (% FSR) to the full-scale value.

Note 3. Refer to 2.6.2 Temperature sensor characteristics/internal reference voltage characteristic.

Note 4. When reference voltage (-) = Vss, the MAX. values are as follows.

Zero-scale error:Add ±0.35%FSR to the MAX. value when reference voltage (-) = AVREFM.Integral linearity error:Add ±0.5 LSB to the MAX. value when reference voltage (-) = AVREFM.Differential linearity error:Add ±0.2 LSB to the MAX. value when reference voltage (-) = AVREFM.



### (2) Interrupt & Reset Mode

### (TA = -40 to +85°C, VPDR $\leq$ VDD $\leq$ 5.5 V, Vss = 0 V)

Parameter	Symbol		Condi	tions	MIN.	TYP.	MAX.	Unit
Voltage detection	VLVDA0	VPOC2,	VPOC1, VPOC0 = 0, 0, 0, fal	ling reset voltage	1.60	1.63	1.66	V
threshold	VLVDA1		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.74	1.77	1.81	V
				Falling interrupt voltage	1.70	1.73	1.77	V
	VLVDA2		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	1.84	1.88	1.91	V
				Falling interrupt voltage	1.80	1.84	1.87	V
	VLVDA3		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	2.86	2.92	2.97	V
				Falling interrupt voltage	2.80	2.86	2.91	V
	VLVDB0	VPOC2,	VPOC1, VPOC0 = 0, 0, 1, fal	ling reset voltage	1.80	1.84	1.87	V
VL VL VL	VLVDB1		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.94	1.98	2.02	V
				Falling interrupt voltage	1.90	1.94	1.98	V
	VLVDB2	VLVDB2	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.05	2.09	2.13	V
				Falling interrupt voltage	2.00	2.04	2.08	V
	VLVDB3		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.07	3.13	3.19	V
				Falling interrupt voltage	3.00	3.06	3.12	V
	VLVDC0	VPOC2,	VPOC1, VPOC0 = 0, 1, 0, falling reset voltage		2.40	2.45	2.50	V
	VLVDC1	1 [	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.56	2.61	2.66	V
				Falling interrupt voltage	2.50	2.55	2.60	V
	VLVDC2		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.66	2.71	2.76	V
				Falling interrupt voltage	2.60	2.65	2.70	V
	VLVDC3		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.68	3.75	3.82	V
				Falling interrupt voltage	3.60	3.67	3.74	V
	VLVDD0	VPOC2,	VPOC1, VPOC0 = 0, 1, 1, fal	ling reset voltage	2.70	2.75	2.81	V
	VLVDD1		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.86	2.92	2.97	V
				Falling interrupt voltage	2.80	2.86	2.91	V
	VLVDD2		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.96	3.02	3.08	V
				Falling interrupt voltage	2.90	2.96	3.02	V
	VLVDD3	1	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.98	4.06	4.14	V
				Falling interrupt voltage	3.90	3.98	4.06	V

# 2.6.7 Power supply voltage rising slope characteristics

### (TA = -40 to +85°C, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until VDD reaches the operating voltage range shown in 2.4 AC Characteristics.



#### 2.7 **RAM Data Retention Characteristics**

(TA = -40 to +85°C, Vss = 0V)						
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 Note		5.5	V

The value depends on the POR detection voltage. When the voltage drops, the RAM data is retained before a POR reset Note is effected, but RAM data is not retained when a POR reset is effected.



#### 2.8 **Flash Memory Programming Characteristics**

$(1A = -40 tO + 60 C, 1.6 V \le VDD \le 0.5 V, VSS = 0 V$	$(T_A = -40 \text{ to } +85^{\circ}\text{C}.)$	$1.8 \text{ V} \leq \text{VDD} \leq 5.5$	V. Vss = $0$ V)
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Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclk	$1.8~V \leq V_{DD} \leq 5.5~V$	1		32	MHz
Number of code flash rewrites Notes 1, 2, 3	Cerwr	Retained for 20 years Ta = 85°C	1,000			Times
Number of data flash rewrites Notes 1, 2, 3		Retained for 1 year TA = 25°C		1,000,000		
		Retained for 5 years TA = 85°C	100,000			
		Retained for 20 years TA = 85°C	10,000			

Note 1. 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

Note 2. When using flash memory programmer and Renesas Electronics self-programming library

Note 3. These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

#### 2.9 **Dedicated Flash Memory Programmer Communication (UART)**

#### (TA = -40 to +85°C, 1.8 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps



Operation of products rated "G: Industrial applications (TA = -40 to +  $105^{\circ}C$ )" at ambient operating temperatures above  $85^{\circ}C$  differs from that of products rated "A: Consumer applications" and "D: Industrial applications" in the ways listed below.

Parameter	A: Consumer applications, D: Industrial applications	G: Industrial applications
Operating ambient temperature	TA = -40 to +85°C	TA = -40 to +105°C
Operating mode	HS (high-speed main) mode:	HS (high-speed main) mode only:
Operating voltage range	$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{@}1 \text{ MHz to } 32 \text{ MHz}$	$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{@}1 \text{ MHz}$ to $32 \text{ MHz}$
	2.4 V $\leq$ VDD $\leq$ 5.5 V@1 MHz to 16 MHz	2.4 V $\leq$ VDD $\leq$ 5.5 V@1 MHz to 16 MHz
	LS (low-speed main) mode:	
	1.8 V $\leq$ VDD $\leq$ 5.5 V@1 MHz to 8 MHz	
	LV (low-voltage main) mode:	
	1.6 V $\leq$ VDD $\leq$ 5.5 V@1 MHz to 4 MHz	
High-speed on-chip oscillator	$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$ :	$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$ :
clock accuracy	±1.0% @ TA = -20 to +85°C	±2.0% @ TA = +85 to +105°C
	±1.5% @ TA = -40 to -20°C	±1.0% @ TA = -20 to +85°C
	$1.6 \text{ V} \le \text{V}_{\text{DD}} < 1.8 \text{ V}$ :	±1.5% @ TA = -40 to -20°C
	±5.0% @ TA = -20 to +85°C	
	±5.5% @ TA = -40 to -20°C	
Serial array unit	UART	UART
	CSI: fcLk/2 (16 Mbps supported), fcLk/4	CSI: fclk/4
	Simplified I <sup>2</sup> C communication	Simplified I <sup>2</sup> C communication
IICA	Standard mode	Standard mode
	Fast mode	Fast mode
	Fast mode plus	
Voltage detector	• Rising: 1.67 V to 4.06 V (14 stages)	• Rising: 2.61 V to 4.06 V (8 stages)
	Falling: 1.63 V to 3.98 V (14 stages)	• Falling: 2.55 V to 3.98 V (8 stages)

**Remark** The electrical characteristics of products rated "G: Industrial applications (TA = -40 to + 105°C)" at ambient operating temperatures above 85°C differ from those of products rated "A: Consumer applications" and "D: Industrial applications". For details, refer to **3.1** to **3.10**.



- Note 1. Total current flowing into VDD and EVDD0, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0 or Vss, EVss0. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
- Note 2. When high-speed on-chip oscillator and subsystem clock are stopped.
- **Note 3.** When high-speed system clock and subsystem clock are stopped.
- **Note 4.** When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
- **Note 5.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below. HS (high-speed main) mode:  $2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{@}1 \text{ MHz}$  to 32 MHz
  - 2.4 V  $\leq$  VDD  $\leq$  5.5 V@1 MHz to 16 MHz
- Remark 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
- Remark 2. fHoco: High-speed on-chip oscillator clock frequency (64 MHz max.)
- Remark 3. fin: High-speed on-chip oscillator clock frequency (32 MHz max.)
- **Remark 4.** fsuB: Subsystem clock frequency (XT1 clock oscillation frequency)
- Remark 5. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C



- Note 1. Total current flowing into VDD and EVDD0, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0 or Vss, EVss0. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
- Note 2. During HALT instruction execution by flash memory.
- Note 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- Note 4. When high-speed system clock and subsystem clock are stopped.
- **Note 5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.
- Note 6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
- Note 7.Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.<br/>HS (high-speed main) mode:  $2.7 \text{ V} \le \text{Vdd} \le 5.5 \text{ V}$ @1 MHz to 32 MHz
  - 2.4 V  $\leq$  VDD  $\leq$  5.5 V@1 MHz to 16 MHz
- Note 8. Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remark 1. fMX: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
- Remark 2. fHOCO: High-speed on-chip oscillator clock frequency (64 MHz max.)
- Remark 3. fill: High-speed on-chip oscillator clock frequency (32 MHz max.)
- Remark 4. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- Remark 5. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C



#### Parameter Symbo Conditions MIN. TYP. MAX. fносо = 64 MHz, $V_{DD} = 5.0 V$ 2.6 Supply DD1 Operat-HS (high-speed main) Basic current ing mode mode Note 5 fill = 32 MHz Note 3 operation VDD = 3.0 V 2.6 Note 1 fносо = 32 MHz. Basic VDD = 5.0 V 2.3 fiH = 32 MHz Note 3 operation VDD = 3.0 V 2.3 fносо = 64 MHz, VDD = 5.0 V HS (high-speed main) Normal 5.4 10.9 mode Note 5 fiH = 32 MHz Note 3 operation $V_{DD} = 3.0 V$ 54 10.9 VDD = 5.0 V 10.3 fносо = 32 MHz. Normal 5.0 fin = 32 MHz Note 3 operation VDD = 3.0 V 10.3 5.0 VDD = 5.0 V fHOCO = 48 MHz. 42 82 Normal fiH = 24 MHz Note 3 operation VDD = 3.0 V 4.2 8.2 fносо = 24 MHz, Normal VDD = 5.0 V 4.0 7.8 fill = 24 MHz Note 3 operation VDD = 3.0 V 40 78 fносо = 16 MHz, Normal VDD = 5.0 V 3.0 5.6 fin = 16 MHz Note 3 operation VDD = 3.0 V 3.0 5.6 HS (high-speed main) 3.4 f<sub>MX</sub> = 20 MHz Note 2 Normal Square wave input 6.6 mode Note 5 VDD = 5.0 V operation Resonator connection 3.6 6.7 f<sub>MX</sub> = 20 MHz Note 2, Normal Square wave input 34 6.6 operation $V_{DD} = 3.0 V$ Resonator connection 3.6 6.7 fmx = 10 MHz Note 2, 2.1 3.9 Normal Square wave input VDD = 5.0 V operation Resonator connection 22 4.0 f<sub>MX</sub> = 10 MHz Note 2. Normal Square wave input 2.1 3.9 VDD = 3.0 V operation Resonator connection 2.2 4.0 fsub = 32.768 kHz Note 4 49 71 Subsystem clock Normal Square wave input operation operation $T_A = -40^{\circ}C$ Resonator connection 4.9 7.1 fsub = 32.768 kHz Note 4 Normal Square wave input 4.9 7.1 $T_A = +25^{\circ}C$ operation 4.9 7.1 Resonator connection Normal 5.1 8.8 fsub = 32.768 kHz Note 4 Square wave input $T_A = +50^{\circ}C$ operation 8.8 Resonator connection 5.1 10.5 fsub = 32.768 kHz Note 4 Square wave input 5.5 Normal TA = +70°C operation Resonator connection 5.5 10.5 fsub = 32.768 kHz Note 4 Normal 6.5 14.5 Square wave input TA = +85°C operation 6.5 14.5 Resonator connection

fsub = 32.768 kHz Note 4

 $T_{A} = +105^{\circ}C$ 

Normal

operation

Square wave input

Resonator connection

### (2) Flash ROM: 96 to 256 KB of 30- to 100-pin products

#### (TA = -40 to +105°C, 2.4 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

(Notes and Remarks are listed on the next page.)

Unit

mΑ

mΑ

mΑ

μA

13.0

13.0

58.0

58.0

- Note 5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer is in operation.
- **Note 6.** Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- Note 7. Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit is in operation.
- **Note 8.** Current flowing during programming of the data flash.
- Note 9. Current flowing during self-programming.
- Note 10. For shift time to the SNOOZE mode, see 23.3.3 SNOOZE mode in the RL78/G14 User's Manual.
- **Note 11.** Current flowing only to the D/A converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IDAC when the D/A converter operates in an operation mode or the HALT mode.
- **Note 12.** Current flowing only to the comparator circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2, or IDD3 and ICMP when the comparator circuit is in operation.
- Note 13. A comparator and D/A converter are provided in products with 96 KB or more code flash memory.
- Remark 1. fil: Low-speed on-chip oscillator clock frequency
- Remark 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- Remark 3. fcLK: CPU/peripheral hardware clock frequency
- Remark 4. Temperature condition of the TYP. value is TA = 25°C



# 3.4 AC Characteristics

Items	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Instruction cycle (min-	Тсү	Main system	HS (high-speed main)	$2.7~V \leq V_{DD} \leq 5.5~V$	0.03125		1	μs
imum instruction exe- cution time)		clock (fmain) operation	mode	$2.4 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$	0.0625		1	μs
		Subsystem clo	ock (fsub) operation	$2.4~V \leq V_{DD} \leq 5.5~V$	28.5	30.5	31.3	μs
		In the self-	HS (high-speed main)	$2.7~V \leq V_{DD} \leq 5.5~V$	0.03125		1	μs
		program- ming mode	mode	$2.4 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$	0.0625		1	μs
External system clock	fEX	$2.7~V \leq V_{DD} \leq$	5.5 V		1.0		20.0	MHz
frequency		$2.4~V \leq V_{DD} \leq$	2.7 V		1.0		16.0	MHz
	fexs				32		35	kHz
External system clock	texн,	$2.7~V \leq V_{DD} \leq$	5.5 V		24			ns
input high-level width,	texl	$2.4~V \leq V_{DD} \leq$	2.7 V		30			ns
low-level width	texhs, texls				13.7			μs
TI00 to TI03, TI10 to	tтін, tті∟				1/fмск + 10			ns
TI13 input high-level width, low-level width					Note			
Timer RJ input cycle	fc	TRJIO		$2.7~V \leq EV \text{DD0} \leq 5.5~V$	100			ns
				$2.4~V \leq EV_{DD0} < 2.7~V$	300			ns
Timer RJ input high-	tтjiн,	TRJIO		$2.7~V \leq EV \text{DD0} \leq 5.5~V$	40			ns
level width, low-level width	t⊤ji∟			$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 2.7 \text{ V}$	120			ns

#### (TA = -40 to +105°C, 2.4 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

NoteThe following conditions are required for low voltage interface when EVDD0 < VDD2.4 V  $\leq EVDD0 < 2.7$  V: MIN. 125 ns

 Remark
 fmck: Timer array unit operation clock frequency

 (Operation clock to be set by the CKSmn bit of timer mode register mn (TMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3))



(				-,			(
Items	Symbol	Conditio	ons	MIN.	TYP.	MAX.	Unit
Timer RD input high-level width, low-level width	ttdih, ttdi∟	TRDIOA0, TRDIOA1, TRDIOE TRDIOC0, TRDIOC1, TRDIO	30, TRDIOB1, D0, TRDIOD1	3/fclk			ns
Timer RD forced cutoff signal	<b>t</b> TDSIL	P130/INTP0	$2MHz < fclk \le 32 MHz$	1			μs
input low-level width			fclk ≤ 2 MHz	1/fclк + 1			
Timer RG input high-level	tтgiн,	TRGIOA, TRGIOB	TRGIOA, TRGIOB				ns
width, low-level width	t⊤GIL						
TO00 to TO03,	fто	HS (high-speed main) mode	$4.0~V \leq EV_{\text{DD0}} \leq 5.5~V$			16	MHz
TO10 to TO13,			$2.7 \text{ V} \le \text{EV}_{\text{DD0}} < 4.0 \text{ V}$			8	MHz
TRJIO0, TRJO0,			$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 2.7 \text{ V}$			4	MHz
TRDIOC0, TRDIOC1,							
TRDIOD0, TRDIOD1,							
TRGIOA, TRGIOB							
output frequency							
PCLBUZ0, PCLBUZ1 output	<b>f</b> PCL	HS (high-speed main) mode	$4.0~V \leq EV_{DD0} \leq 5.5~V$			16	MHz
frequency			$2.7 \text{ V} \le \text{EV}_{\text{DD0}} < 4.0 \text{ V}$			8	MHz
			$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 2.7 \text{ V}$			4	MHz
Interrupt input high-level	tinth,	INTP0	$2.4~V \leq V \text{DD} \leq 5.5~V$	1			μs
width, low-level width	tintl	INTP1 to INTP11	$2.4~V \leq EV_{DD0} \leq 5.5~V$	1			μs
Key interrupt input low-level width	tĸĸ	KR0 to KR7	$2.4 \text{ V} \le \text{EV}_{\text{DD0}} \le 5.5 \text{ V}$	250			ns
RESET low-level width	trsl			10			μs

#### (TA = -40 to +105°C, 2.4 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

(2/2)





#### CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)





- Remark 1. p: CSI number (p = 00, 01, 10, 20, 30, 31), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM number (g = 0, 1, 3 to 5, 14)
- Remark 2. CSI01 of 48-, 52-, 64-pin products, and CSI11 and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

# 3.5.2 Serial interface IICA

#### (TA = -40 to +105°C, 2.4 V $\leq$ EVDD0 = EVDD1 $\leq$ VDD $\leq$ 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) mode			Unit	
			Standard mode		Fast mode		
			MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscl	Fast mode: fc∟ĸ ≥ 3.5 MHz	_	—	0	400	kHz
		Standard mode: fc∟k ≥ 1 MHz	0	100	_	—	kHz
Setup time of restart condition	tsu: sta		4.7		0.6		μs
Hold time Note 1	thd: STA		4.0		0.6		μs
Hold time when SCLA0 = "L"	t∟ow		4.7		1.3		μs
Hold time when SCLA0 = "H"	tніgн		4.0		0.6		μs
Data setup time (reception)	tsu: dat		250		100		ns
Data hold time (transmission) Note 2	thd: dat		0	3.45	0	0.9	μs
Setup time of stop condition	tsu: sto		4.0		0.6		μs
Bus-free time	<b>t</b> BUF		4.7		1.3		μs

Note 1. The first clock pulse is generated after this period when the start/restart condition is detected.

Note 2. The maximum value (MAX.) of the DE DAT is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

Caution The values in the above table are applied even when bit 2 (PIOR02) in the peripheral I/O redirection register 0 (PIOR0) is 1. At this time, the pin characteristics (IOH1, IOL1, VOH1, VOL1) must satisfy the values in the redirect destination.

**Remark** The maximum value of C<sub>b</sub> (communication line capacitance) and the value of R<sub>b</sub> (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode: $C_b = 400 \text{ pF}, R_b = 2.7 \text{ k}\Omega$ Fast mode: $C_b = 320 \text{ pF}, R_b = 1.1 \text{ k}\Omega$ 

#### **IICA** serial transfer timing



**Remark** n = 0, 1



R5F104GAANA, R5F104GCANA, R5F104GDANA, R5F104GEANA, R5F104GFANA, R5F104GGANA, R5F104GHANA, R5F104GJANA

R5F104GADNA, R5F104GCDNA, R5F104GDDNA, R5F104GEDNA, R5F104GFDNA, R5F104GGDNA, R5F104GJDNA, R5F104GJDNA

R5F104GAGNA, R5F104GCGNA, R5F104GDGNA, R5F104GEGNA, R5F104GFGNA, R5F104GGGNA,

R5F104GHGNA, R5F104GJGNA

R5F104GKANA, R5F104GLANA

R5F104GKGNA, R5F104GLGNA



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R5F104LCAFB, R5F104LDAFB, R5F104LEAFB, R5F104LFAFB, R5F104LGAFB, R5F104LHAFB, R5F104LJAFB

R5F104LCDFB, R5F104LDDFB, R5F104LEDFB, R5F104LFDFB, R5F104LGDFB, R5F104LHDFB, R5F104LJDFB

R5F104LCGFB, R5F104LDGFB, R5F104LEGFB, R5F104LFGFB, R5F104LGGFB, R5F104LHGFB, R5F104LJGFB

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP64-10x10-0.50	PLQP0064KF-A	P64GB-50-UEU-2	0.35



Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

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R5F104LCAFP, R5F104LDAFP, R5F104LEAFP, R5F104LFAFP, R5F104LGAFP, R5F104LHAFP, R5F104LJAFP R5F104LCDFP, R5F104LDDFP, R5F104LEDFP, R5F104LFDFP, R5F104LGDFP, R5F104LHDFP, R5F104LJDFP R5F104LCGFP, R5F104LDGFP, R5F104LEGFP, R5F104LFGFP, R5F104LGGFP, R5F104LHGFP, R5F104LJGFP

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP64-14x14-0.80	PLQP0064GA-A	P64GC-80-GBW-1	0.7



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#### R5F104MKAFB, R5F104MLAFB R5F104MKGFB, R5F104MLGFB



